



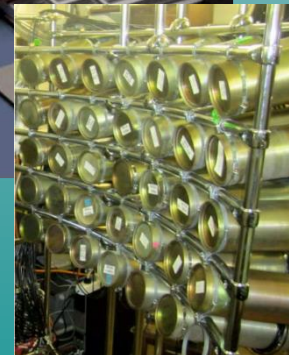
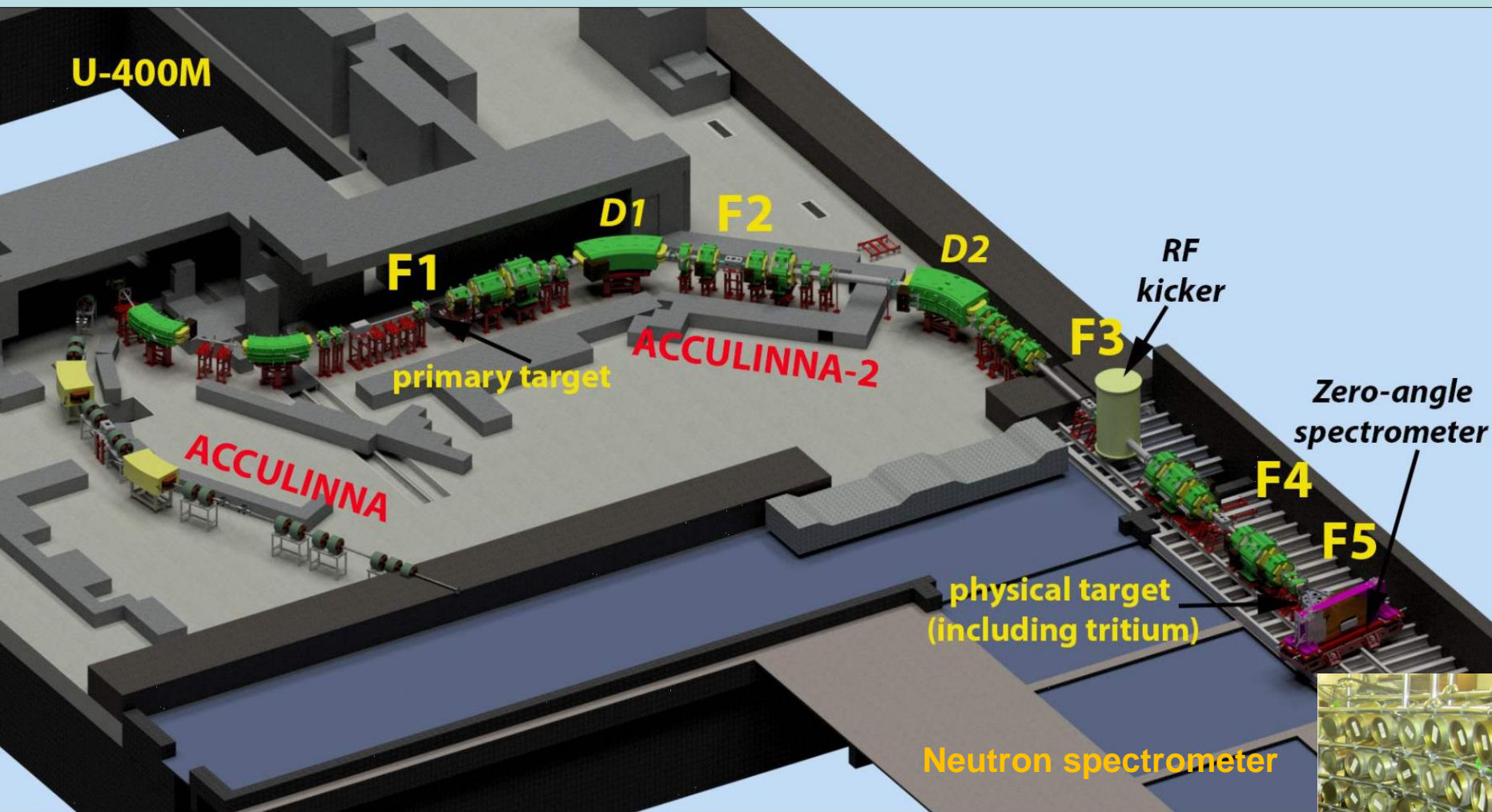
A Monte Carlo based method for fine calibration of Si Telescopes

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Outline

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- Configurations and methods of calibration measurements
- Calibration results
- Discrepancies
- Summary and wish-list for Geant4



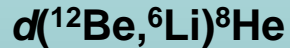
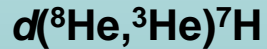
A.S. Fomichev, L.V. Grigorenko, S.A. Krupko, S.V. Stepantsov and G.M. Ter-Akopian
The ACCULINNA-2 project: The physics case and technical challenges,
Eur. Phys. J. A 54, 97 (2018)

Introduction

The photo is of April 2017.

Currently the separator is hidden inside the radiation shielding and fully operational, except for the RF kicker which is just delivered

Some of the reactions to be studied soon



	ACC	ACC-2
	FLNR, JINR	
$\Delta\Omega$, msr	0.9	5.8
δ_p , %	2.5	6.0
$p/\Delta p$, a.u.	1000	2000
$B\rho_{\text{max}}$, Tm	3.2	3.9
Length, m	21	38
E_{min} , AMeV	10	5
E_{max} , AMeV	40	50

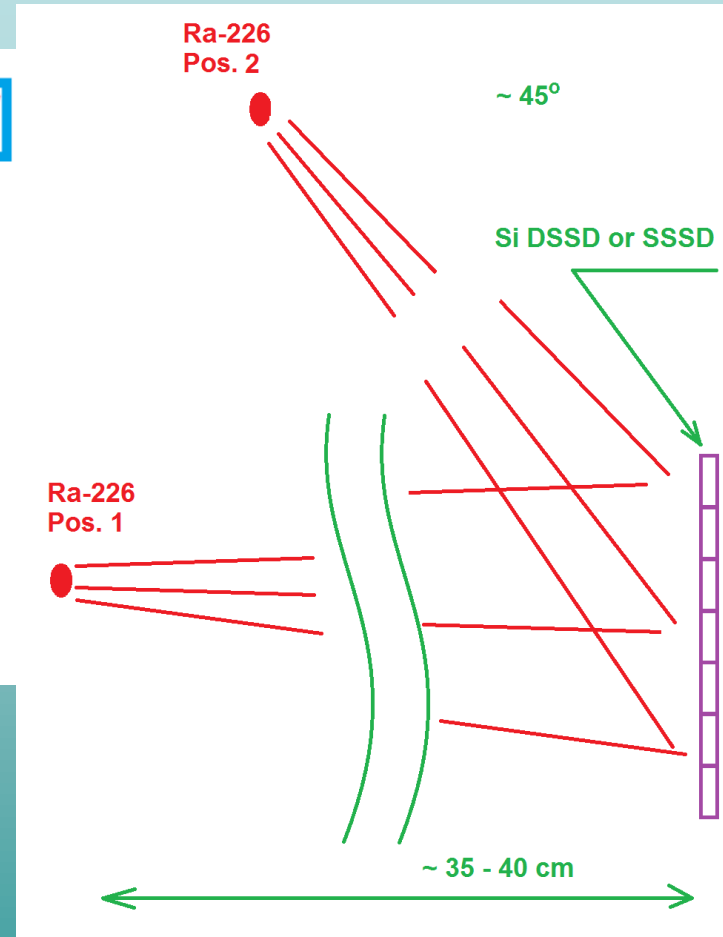
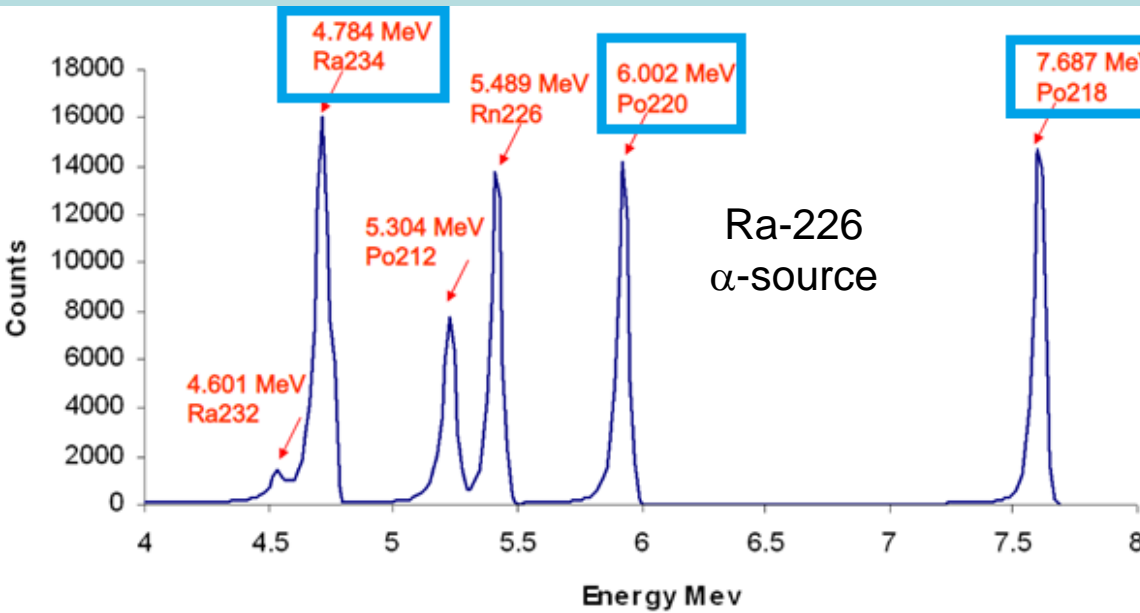
Introduction

Specificity of the experiments at ACCULINNA-2.

- Low energy multiply charged ions produce big and non-constant energy loss.
- Inevitable part of calibration procedure is to measure the dead layers of the detectors, especially Si ones (because of rel. good energy resolution)
- For DeltaE-E discrimination a thin Si detector is used which is substantially non-uniform
- All together require calibration measurements with high statistics and should be supported by reliable MC simulations.

Configurations and methods of calibration measurements

1) Traditional approach. Big distance, separate measurements for the dead layers.



Shift of peaks is due to increasing range of α -particles in the dead layer. **Drawbacks:** long measurement ~ 12 h; different thickness of the dead layer is found for different peaks; possible small change of the amplification after switching OFF and ON matters; depends on the energy loss calculation method (we compared LISE++ and Geant4).

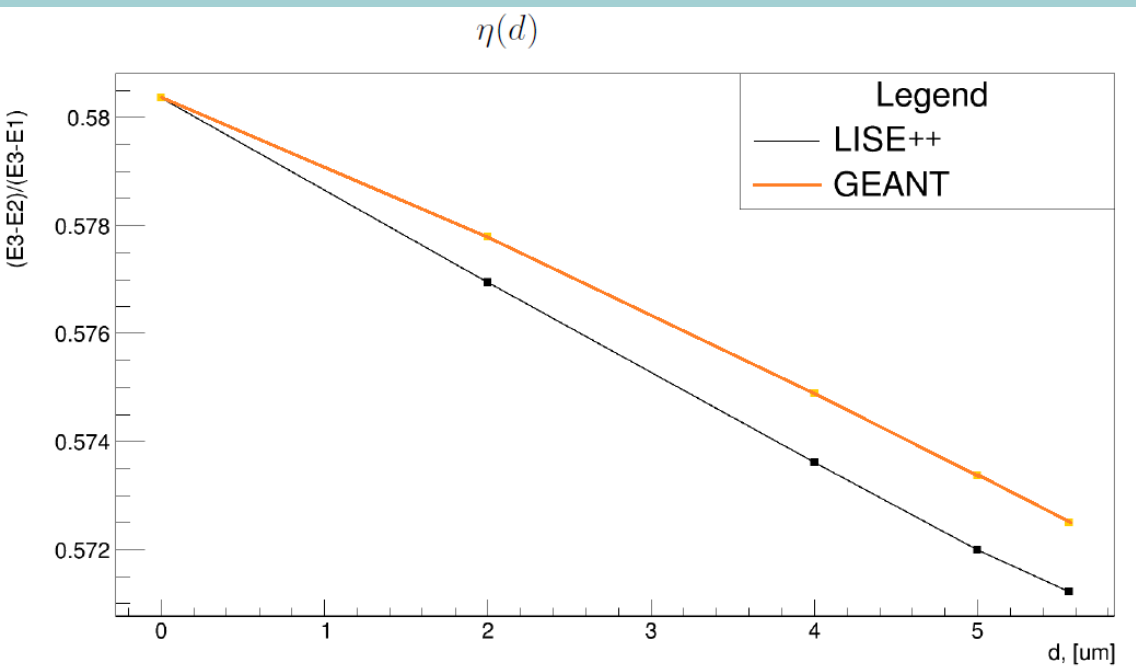
Configurations and methods of calibration measurements

2) Alternative approach. Simultaneous measurement for dead layers and calibration. Lines of 4.7844 MeV, 6.0024 MeV, 7.6869 MeV are used.

Let's consider the following dimensionless ratio:

$$\eta(d) = \frac{E_3 - E_2}{E_3 - E_1}, \text{ where } E_1, E_2 \text{ and } E_3 \text{ are the energies}$$

of alpha particles with initial energies 4.7844, 6.0024 and 7.6869 MeV respectively, after propagation through the dead layer with thickness d [μm].



If the response function of each strip is linear ($E_{dep} = a \cdot N_{ADC} + b$), then $\eta = \eta_{exp}$

$$\eta_{exp}(d) = \frac{N_3 - N_2}{N_3 - N_1}$$

There is still a discrepancy between Geant4 and LISE++ Eloss calculations.

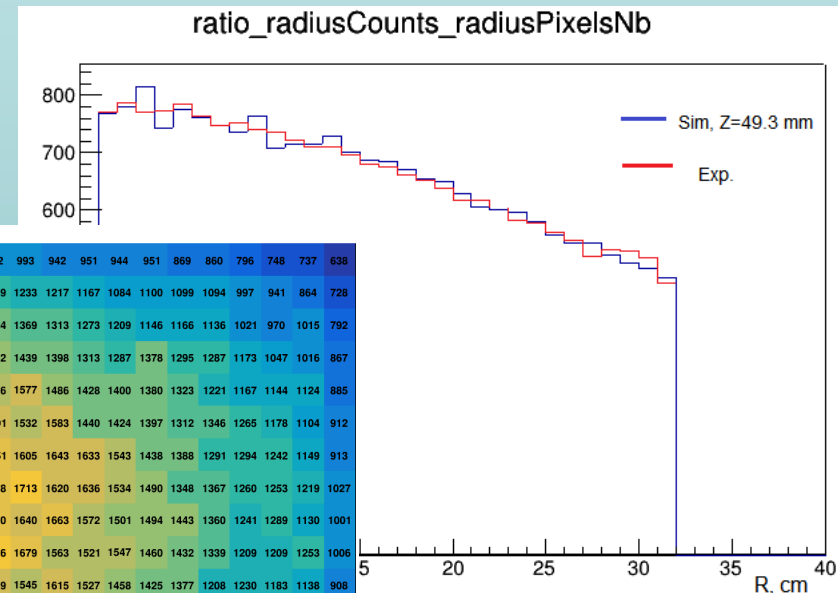
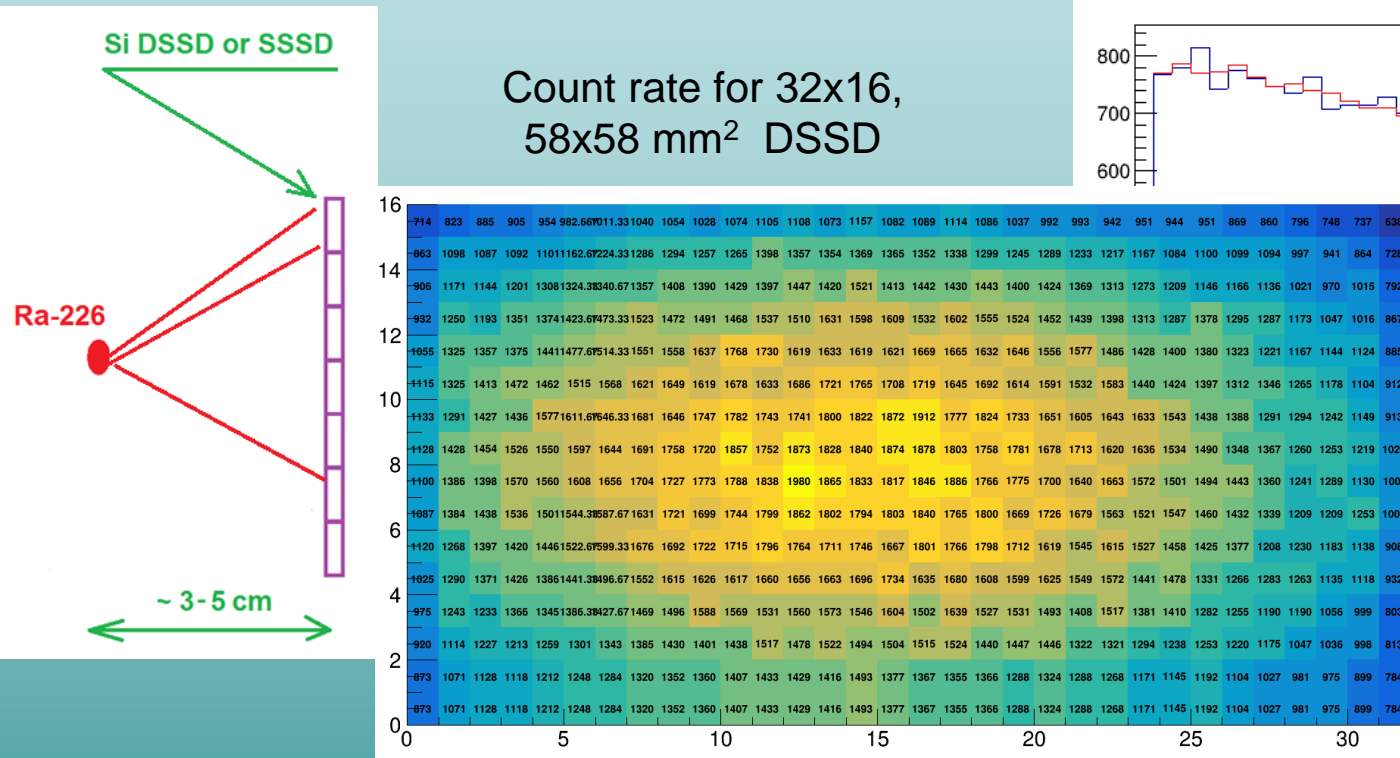
After d is found, calibration can be easily accomplished.

Implausible d is a sign of nonlinearity

A combined method with 2 sources at different incidence angles is proposed for the future for handling weak non-linearities.

Configurations and methods of calibration measurements

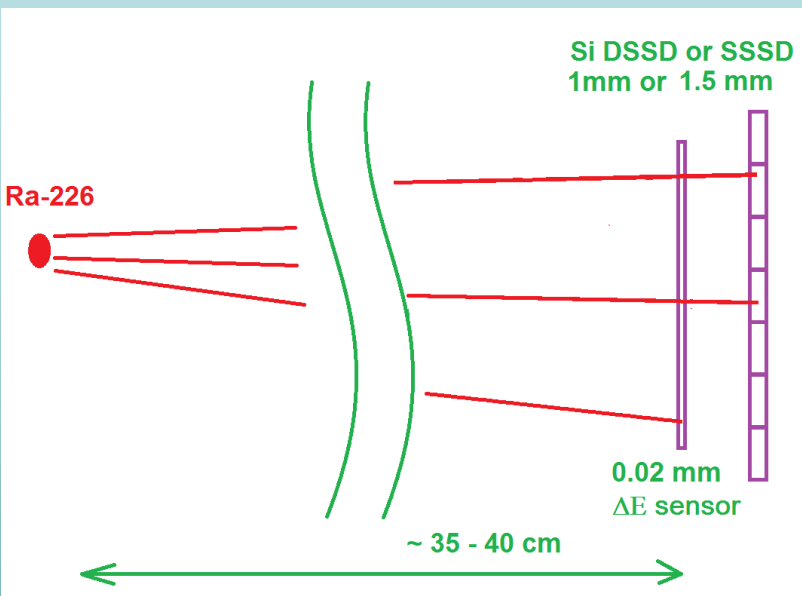
3) “Even more alternative” approach. The source is placed much closer. Simultaneous measurement for dead layers and calibration. Lines of 4.7844 MeV, 6.0024 MeV, 7.6869 MeV are used.



Measurements at a small distance are much faster. However in order to take into account correctly the distribution of ranges of α -particle in the dead layer of each “pixel”, simulations are used. This distribution depends on the incidence angle.

Configurations and methods of calibration measurements

4) Calibration of a telescope consisting of a thin ΔE detector assembled together with a thick one. Lines of 4.7844 MeV, 6.0024 MeV, 7.6869 MeV are used.



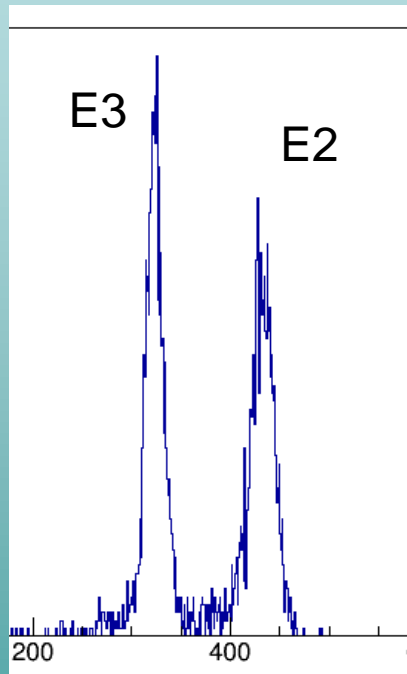
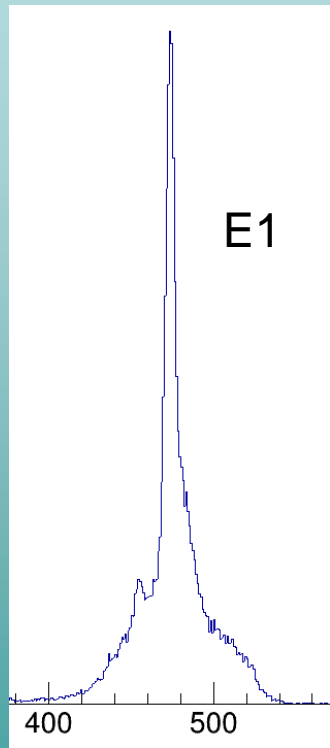
14	23.32	23.54	23.89	24.31	24.40	24.17	23.73	22.90	22.05	21.21	20.21	19.16	18.36	17.73	17.09	16.56
13	23.58	23.94	24.32	24.77	24.93	24.75	24.18	23.60	22.59	21.84	20.79	19.63	18.74	17.90	17.36	16.88
12	23.93	24.32	25.00	25.44	25.57	25.40	24.88	24.32	23.48	22.51	21.55	20.45	19.02	18.30	17.47	16.65
11	23.99	24.62	25.29	25.95	26.03	25.85	25.29	24.67	23.75	22.91	22.08	20.78	19.62	18.45	17.36	16.55
10	24.04	24.68	25.58	26.08	26.35	26.20	25.68	24.79	23.87	23.16	22.27	21.32	20.00	18.66	17.40	16.36
9	23.99	24.75	25.70	26.27	26.43	26.23	25.65	24.87	23.85	23.14	22.54	21.52	20.35	19.07	17.65	16.37
8	23.92	24.84	26.00	26.52	26.72	26.18	25.53	24.74	23.85	23.29	22.54	21.48	20.50	19.45	18.03	16.61
7	23.66	24.68	25.88	26.59	26.70	26.10	25.48	24.68	23.93	23.16	22.30	21.29	20.47	19.50	18.23	16.93
6	23.68	24.48	25.67	26.41	26.79	26.35	25.91	25.00	23.94	23.06	22.11	21.20	20.32	19.34	18.14	17.03
5	23.47	24.27	25.30	26.08	26.37	26.18	25.82	24.78	23.77	22.84	21.86	21.10	20.36	19.33	18.21	17.18
4	23.22	23.94	24.99	25.53	25.73	25.66	25.10	24.19	23.30	22.47	21.72	21.02	20.32	19.45	18.56	17.56
3	23.04	23.79	24.39	24.98	25.11	24.82	24.30	23.52	22.77	22.08	21.54	20.88	20.26	19.51	18.67	17.81
2	22.81	23.29	23.90	24.30	24.38	24.06	23.30	22.65	21.88	21.41	20.94	20.37	19.92	19.46	18.83	18.03
1	22.35	23.01	23.41	23.75	23.56	22.98	22.32	21.61	20.94	20.56	20.12	19.65	19.38	19.30	18.90	18.35
0	22.27	22.76	23.15	23.36	22.93	22.35	21.69	20.84	20.38	19.93	19.55	19.24	19.09	19.09	18.87	18.57

First task is to measure the passive thickness of the ΔE detector. One can use the η -ratio or shift of the peaks w.r.t measurements without the ΔE detector. In the last case the obtained thickness slightly depends on the chosen initial energy of α -particles and in neither case coincide with measurement based on the η -ratio. However the difference is not more than 1.5 micron

Configurations and methods of calibration measurements

4) Calibration of the thin ΔE detector assembled together with a thick one. Lines of 4.7844 MeV, 6.0024 MeV, 7.6869 MeV are used.

The second task is calibration of the ΔE detector itself. Each readout channel corresponds to a strip with non-constant thickness. We consider the thickest and the thinnest “pixels” of the strip.



Case 1. 4.784 MeV alphas stop in the sensor, others go through.

E1 – Eloss of the stopped particles

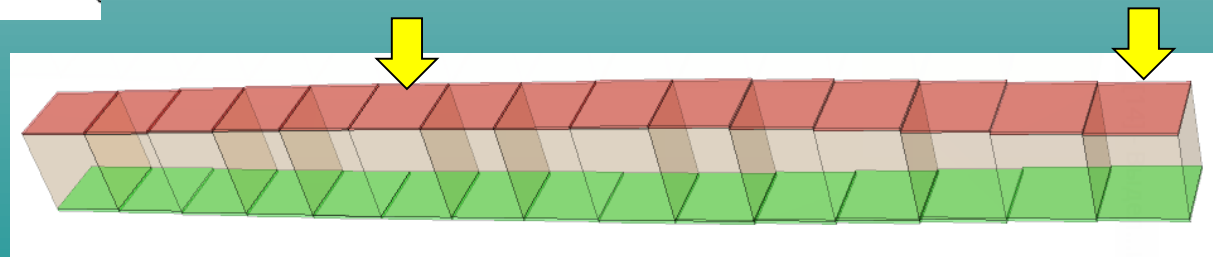
E2, E3 – Eloss in the thick “pixel”,

E2', E3' – in the thin one

Case 2. All three lines of interest go through the ΔE detector.

E1, E2, E3 – Eloss in the thick “pixel”,

E1', E2', E3' – in the thin one



Configurations and methods of calibration measurements

4) Calibration of the thin ΔE detector assembled together with a thick one. Lines of 4.7844 MeV, 6.0024 MeV, 7.6869 MeV are used.

The second task is calibration of the ΔE detector itself. Each readout channel corresponds to a strip with non-constant thickness. Consider the thickest and the thinnest pixel of the strip.

We can compute and compare with simulation several dimensionless ratios

$$\eta_1 = (E1-E2)/(E1-E3), \eta_2 = (E2-E2')/(E3-E3'); \eta_3 = (E2'-E3')/(E2-E3); \eta_4 = (E2'-E3)/(E2-E3').$$

η_1 -ratio allows to determine the active thickness of a “pixel” if the front dead layer is known

There is no time to go into detail, but...

- There is a discrepancy between LISE++. Geant4 and experiment.
- Geant4 is closer to the experiment.
- There is no sensitivity to the dead layers (to be measured separately)
- In the case 2 when all alphas pass through the conclusions are the same

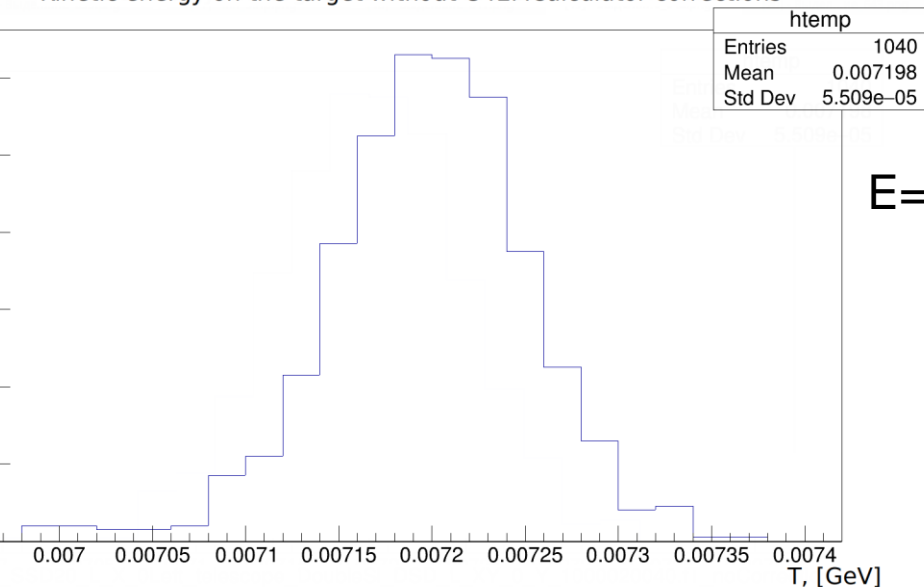
Expected $d_{Active}(\mu m)\downarrow$	Pseudo-pixel	Calc. η_1 LISE	Calc. η_1 Geant4	Experim. η_1	Calc. d_{Act} Geant4
15.16	X15Y10	0.5711	0.5606	0.5628	15.36
15.89	X14Y14	0.5768	0.5699	0.5527	14.51
17.37	X15Y0	0.5910	0.5895	0.5807	16.73
17.70	X14Y1	0.5948	0.5938	0.5783	16.52

Calibration results

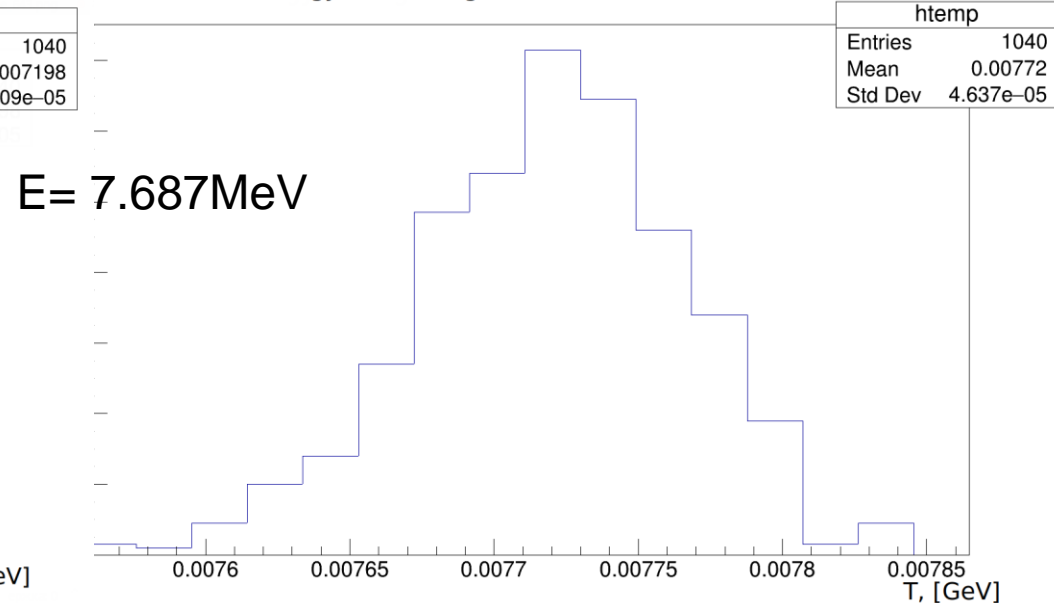
For the working version of calibration we decided to rely on the passive thickness measurements via shift of the most energetic alpha line, assumed the front dead layer to be 0.5 micron (+0.3 micron at the source) and used the active thickness calculated via η_1 -ratio for thicker strips where the 4.78 MeV alphas stop. The achieved accuracy is not worse than 4 keV. For thinner strips we assumed in addition the back dead layer to be 0.7 micron and achieved quality of calibration is worse, up to 68 keV (no optimization is applied).

Reconstruction of energy in a telescope requires reverse tracking of a particle, taking into account the dead layers. This procedure is realized within the ExpertRoot framework(talk by Mikhail Kozlov tomorrow).

Kinetic energy on the target without G4EMCalculator corrections



Kinetic energy on the target with G4EMCalculator corrections



Discrepancies

In this slide the observed discrepancies are listed as well as possible reasons. Some of the reasons may be relevant for Geant4

- MC based measurements of the passive thickness of the thin ΔE detector do not match each other well enough. (instability of the calibration; non-linearity of the response; inaccuracy of the Eloss simulation for low energy ions, wrong understanding of the dead layer)
- MC based measurements of the active thickness of the thin ΔE detector do not match each other well enough. (inaccuracy of the Eloss simulation for low energy ions, wrong understanding of the dead layer)
- G4EMCalculator seems to overestimate losses w.r.t simulation for a few keV
- Spread of Eloss in the thin ΔE detector is bigger than expected from simulations taking into account thickness nonuniformity and resolution If the detector (inaccuracy of the simulations of the Eloss fluctuations, detector surface is less smooth than we think, wrong understanding of the dead layer)

Summary and wish-list for Geant4

A Monte Carlo based method for fine calibration of Si Telescopes is developed. It is sensitive to accuracy of the energy loss simulations and to imperfectness (of different nature) of the detector. For improving the quality of the calibration it is desirable to decouple validation of the simulation from the other factors. Our wish-list is completely about validation.

- It would be nice to have a clear navigation through all the accomplished works concerning validation of the energy loss, straggling and multiple scattering models in G4 for low energy multiply charged ions
- The G4 site could be a place where the information about all planned and ongoing validation activities is concentrated.
- We would be happy to join validation activity coordinated by the G4 physics experts.

Thank you for your attention

Calculated Secondary Beam Intensity

HI	I_{HI} , pμA	E, A·MeV	RIB	E, A·MeV	I, pps/pμA	Purity, %	Exper.
⁷ Li	4	34	⁶ He	28	3.5×10^7	98	
			⁶ He	6	2.1×10^5	98	
			⁷ Be	22,4	5.9×10^5	70	
¹¹ B	5	33	⁸ He	21,9	8.6×10^4	98	¹⁰ He
			⁸ He	15,6	3.7×10^4	98	
			⁸ B	15,8	2.2×10^6	28	
¹⁵ N	1.0-1.5	47	¹¹ Li	33,2	7.2×10^3	98	⁷ H, ¹⁰ Li
¹⁸ O	0.2 => 2 extraction upgrade	48	¹¹ Li	31,3	7.4×10^3	81	
			¹⁴ Be	34,6	1.6×10^3	98	¹⁶ Be
			¹⁵ B	32,1	4.3×10^5	96	
			¹⁶ C	28,8	2.8×10^7	98	
²⁰ Ne	1.0-1.5	54	¹³ O	24,2	1.5×10^6	10	¹² O
			¹⁴ O	22,8	3.4×10^7	54	
			¹⁷ Ne	29	5.4×10^6	0.5% or 69% with RF-K	¹⁶ Ne, ¹⁷ Ne
³⁶ S	0.1 => 1.0 ECR18/SC	49	²⁴ O	23,4	2.5×10^3	62	
			¹⁴ Be	29,2	3.8×10^3	67	
			¹⁷ C	25	1.1×10^5	78	
			¹⁸ C	25,5	1.9×10^4	11	
³² S	0.1 => 1.0	52	²⁴ Si	11,3	7.2×10^3	31	
			²⁷ S	23,2	1.3×10^2	0.5% or 2% with RF-K	²⁶ S, ²⁷ S

Included into Lise++(O. Tarasov & D.Bazin): http://lise.nsl.msui.edu/9_4/acculinna2/

Dead (μm) \rightarrow η_i \downarrow (strip 6)	0	0.5	0.8	1.0	Exp. strip 6	Geant4 Dead 0.8	Exp. strip 7	G4 d0.8 strip7
η_2	1.559	1.558	1.558	1.558	1.587	1.575	1.526	1.529
η_3	0.666	0.665	0.666	0.665	0.659	0.6617	0.6823	0.6819
η_4	0.438	0.0416	0.0417	0.0397	0.0500	0,0466	0,0486	0.0498

Dead (μm) \rightarrow Active(μm) \downarrow	0	0.5	0.8	1.0	Exp. X0Y6	Exp. X6Y6	Geant4 Dead 0.8
20.08				0.6647	0.6638	0.2759	
20.284			0.6639				
20.491	-	-	-	-			0,6639
20.568		0.6639					
21.04	0.6632						
24.35				0.2761			
24.558			0.2759				
24.753	-	-	-	-			0,2759
24.87		0.2759					
25.39	0.2763						
Above: η_1 values; below: calculated back dead layer							
Back dead X0Y6 (μm)	-	0.92	0.91	0.91	-	-	0.70
Back dead X6Y6 (μm)	-	0.84	0.85	0.86	-	-	0.68